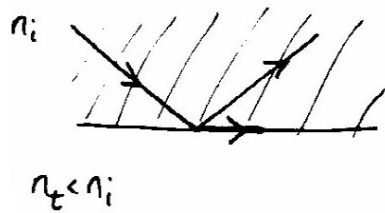


θ_c - critical angle for total int. reflection



$$n_i \sin \theta_c = n_t$$

$$\sin \theta_c = \frac{n_t}{n_i} = n_{ti}$$

for $\theta_i > \theta_c$ treatment is not quite right (evanescent waves)

in general, $t_{\perp} - r_{\perp} = 1$

Case (ii) $\vec{E} \parallel$ to plane of incidence
 $\Rightarrow \vec{B} \perp$ " " " "

$$ME \Rightarrow E_{oi} \cos \theta_i - E_{or} \cos \theta_r = E_{ot} \cos \theta_t$$

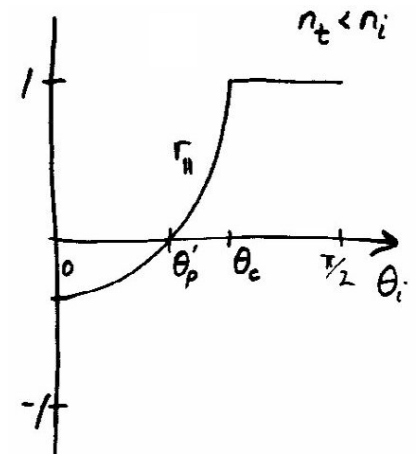
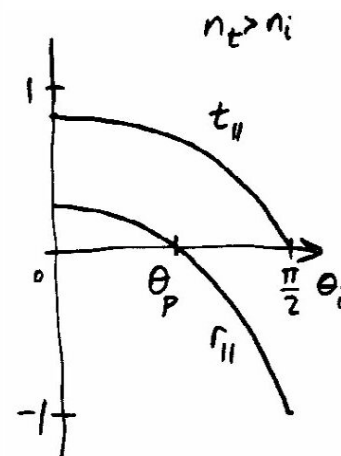
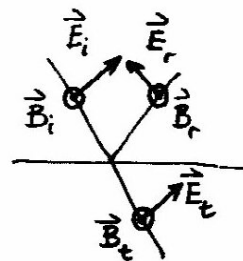
$$n_i E_{oi} + n_r E_{or} = n_t E_{ot}$$

combine: ($\theta_r = \theta_i$)

$$\left(\frac{E_{or}}{E_{oi}} \right)_{\parallel} \equiv r_{\parallel} = \frac{n_t \cos \theta_i - n_i \cos \theta_t}{n_i \cos \theta_t + n_t \cos \theta_i}$$

$$\left(\frac{E_{ot}}{E_{oi}} \right)_{\parallel} \equiv t_{\parallel} = \frac{2n_i \cos \theta_i}{n_i \cos \theta_t + n_t \cos \theta_i}$$

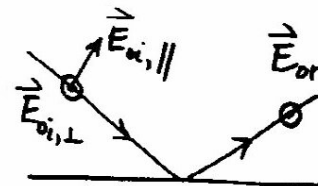
(r's and t's can be further simplified using Snell's law).



note: $t_{\parallel} - r_{\parallel} \neq 1$, but $t_{\parallel} + r_{\parallel} = 1$ at normal incidence
 again, for $\theta > \theta_c$ treatment not quite right.

look at θ_P "Brewster's angle"

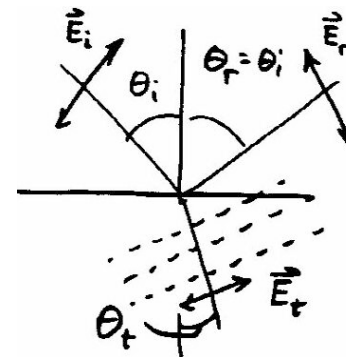
mixed polarized incident:



output only $\perp$ polarization

why?

oscillators don't emit $\perp$ to their oscillation direction:



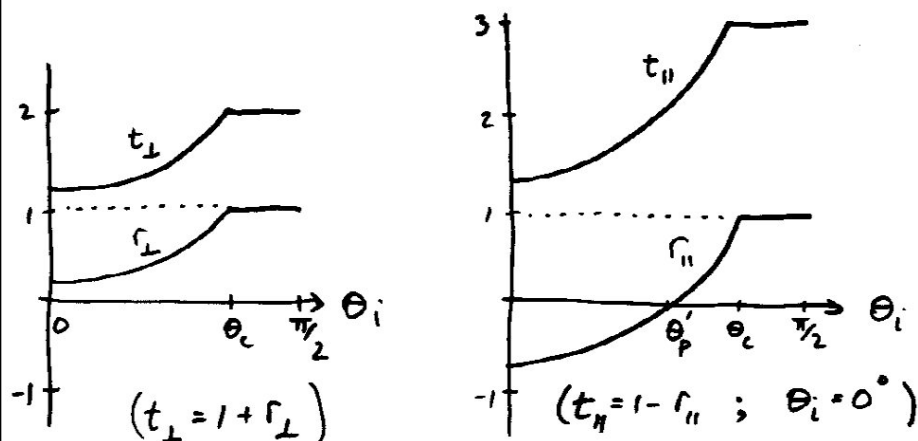
if $\theta_t + \theta_r = \pi/2$ then $E_r = 0$.

$$\theta_t = \pi/2 - \theta_i$$

$$n_i \sin \theta_P = n_t \sin \theta_t = n_t \cos \theta_P$$

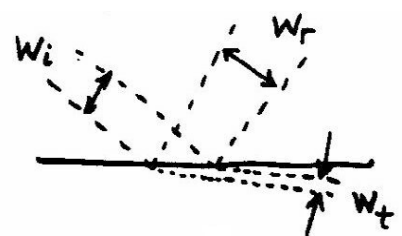
$$\Rightarrow \boxed{\tan \theta_p = \frac{n_t}{n_i}} \quad \text{similarly for } \theta_p'$$

return to examine $t_{\perp}, t_{\parallel}$ for $n_t < n_i$:



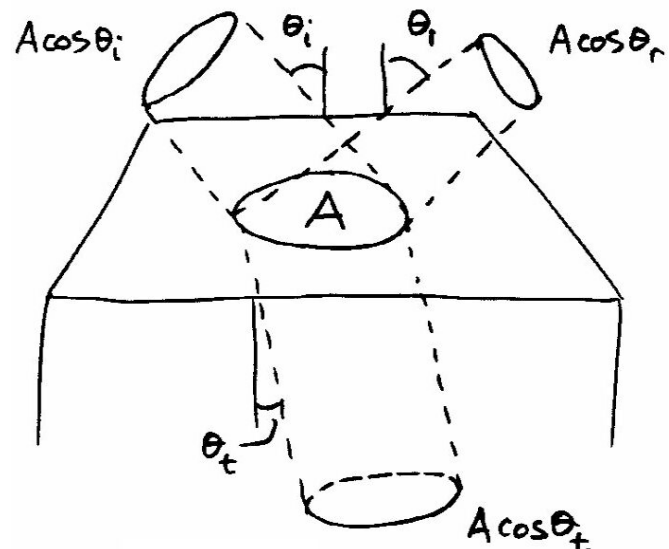
• find large t values! Does this violate conservation of energy?

No! cross-sectional area of beams also varies!



$w_t \rightarrow 0$ for $\theta_t \rightarrow \pi/2$
 $\Rightarrow$ no energy in beam.

in detail:



I_i, I_r, I_t flux densities (intensities) (W/m^2)

$$\text{incident power} = I_i A \cos \theta_i$$

$$\text{reflected " } = I_r A \cos \theta_r$$

$$\text{transmitted " } = I_t A \cos \theta_t$$

then, reflectance $R \equiv \frac{I_r A \cos \theta_r}{I_i A \cos \theta_i} = \frac{I_r}{I_i}$

$$\text{transmittance } T \equiv \frac{I_t A \cos \theta_t}{I_i A \cos \theta_i} = \frac{I_t \cos \theta_t}{I_i \cos \theta_i}$$

relate using $I_i A \cos \theta_i = I_r A \cos \theta_r + I_t A \cos \theta_t$

$$\text{and } I = \frac{n\epsilon}{2} E_o^2 = \frac{cn^2\epsilon_o}{2n} E_o^2 \propto nE_o$$

$$\Rightarrow n_i E_{oi}^2 \cos\theta_i = n_i E_{or}^2 \cos\theta_i + n_t E_{ot}^2 \cos\theta_t$$

$$1 = \left(\frac{E_{or}}{E_{oi}}\right)^2 + \frac{n_t \cos\theta_t}{n_i \cos\theta_i} \left(\frac{E_{ot}}{E_{oi}}\right)^2$$

$$\text{or } \boxed{1 = R + T}$$

also, can write

$$R = \left(\frac{E_{or}}{E_{oi}}\right)^2 = r^2$$

$$T = \frac{n_t \cos\theta_t}{n_i \cos\theta_i} \left(\frac{E_{ot}}{E_{oi}}\right)^2 = \frac{n_t \cos\theta_t}{n_i \cos\theta_i} t^2$$

$$\text{and } R_{\perp} \equiv r_{\perp}^2, \quad R_{\parallel} \equiv r_{\parallel}^2$$

$$T_{\perp} \equiv \frac{n_t \cos\theta_t}{n_i \cos\theta_i} t_{\perp}^2, \quad T_{\parallel} \equiv \frac{n_t \cos\theta_t}{n_i \cos\theta_i} t_{\parallel}^2$$

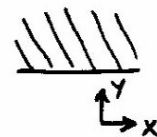
and find

$$R_{\parallel} + T_{\parallel} = 1, \quad R_{\perp} + T_{\perp} = 1$$

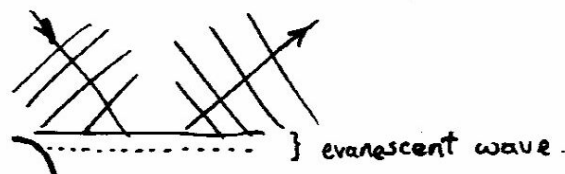
Evanescent Waves ($n_t < n_i, \theta_i > \theta_c$)

- impossible to satisfy boundary conditions with real values of k_y ;

$$\text{need } k_y = i\beta,$$



wave decays exponentially,



turns out, $\beta = \left(\frac{\sin^2 \theta_i}{n_t^2} - 1 \right)^{1/2} \rightarrow 0 \text{ as } \theta \rightarrow \theta_c$

For incident wave of infinite extent,

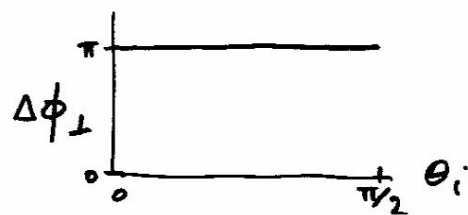


$w_i \rightarrow \infty$, then fraction of power in evanescent wave is zero.

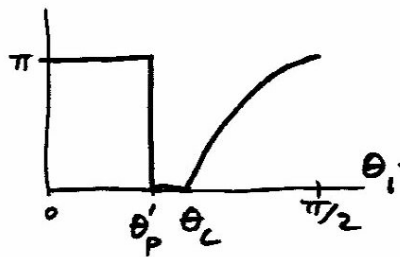
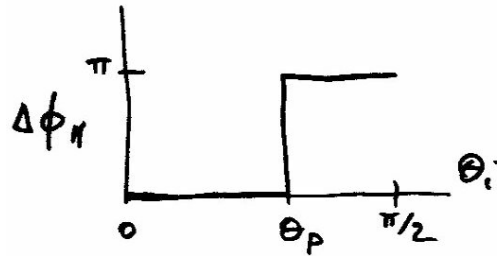
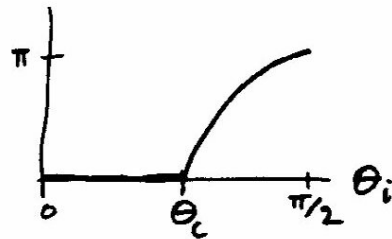
(for finite w_i , then must consider diffraction at edges of incident wave).

Phase Shift of Reflected Wave:

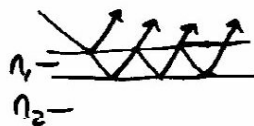
$$n_t > n_i$$



$$n_t < n_i$$

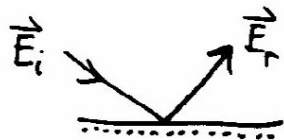


- very important for later applications of eg. multiple reflections in thin films,



- application of Fresnel Egn's:

Ellipsometry



- measure polarization and amp. of reflected beam, vs. ω and/or vs. θ_i . Determine $\tilde{n}$ for material and for thin films on material.